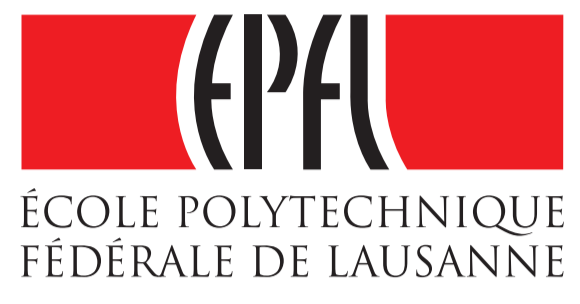


# Polarization mode structure in long-wavelength wafer-fused vertical-cavity surface-emitting lasers (VCSELs)

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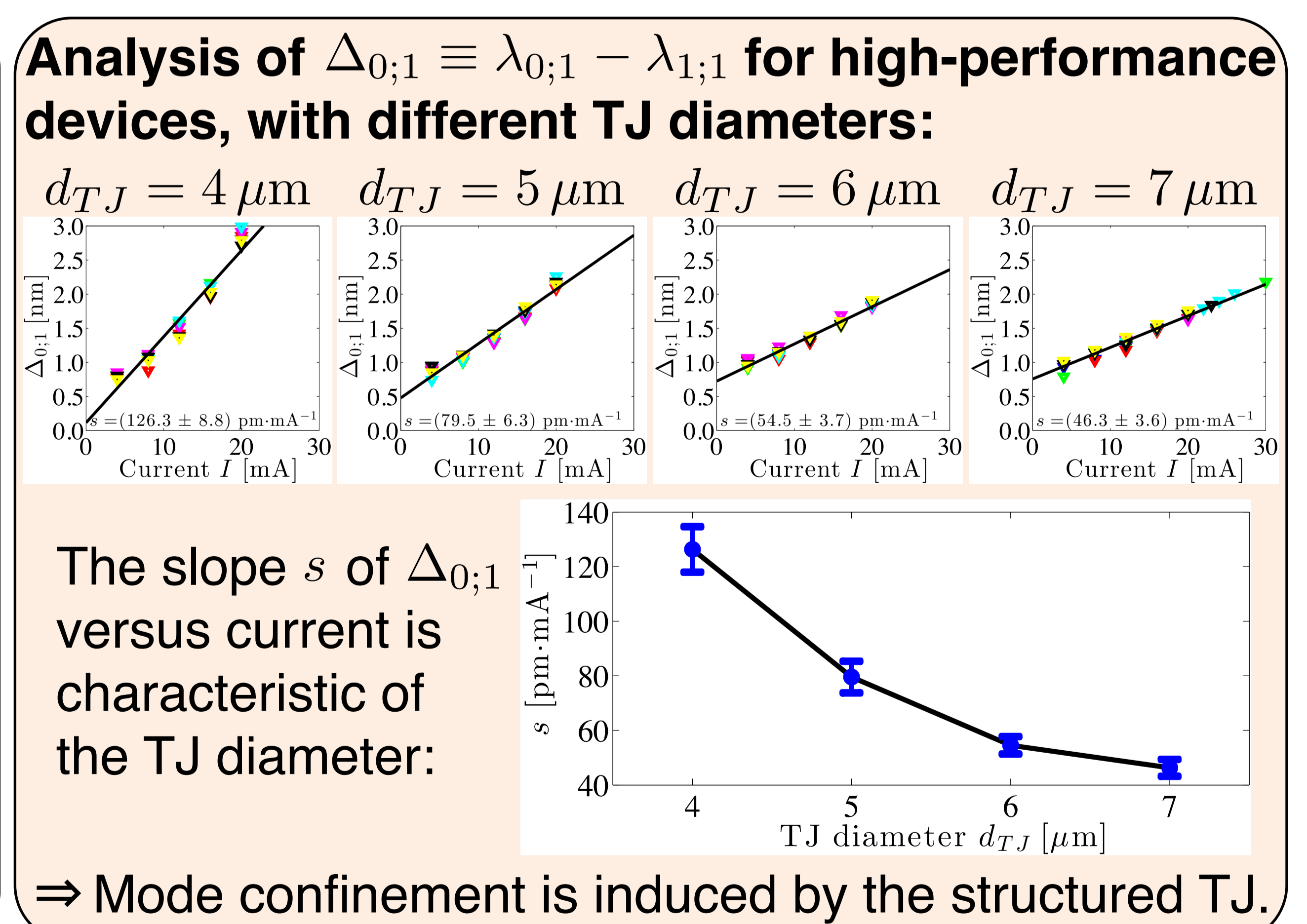
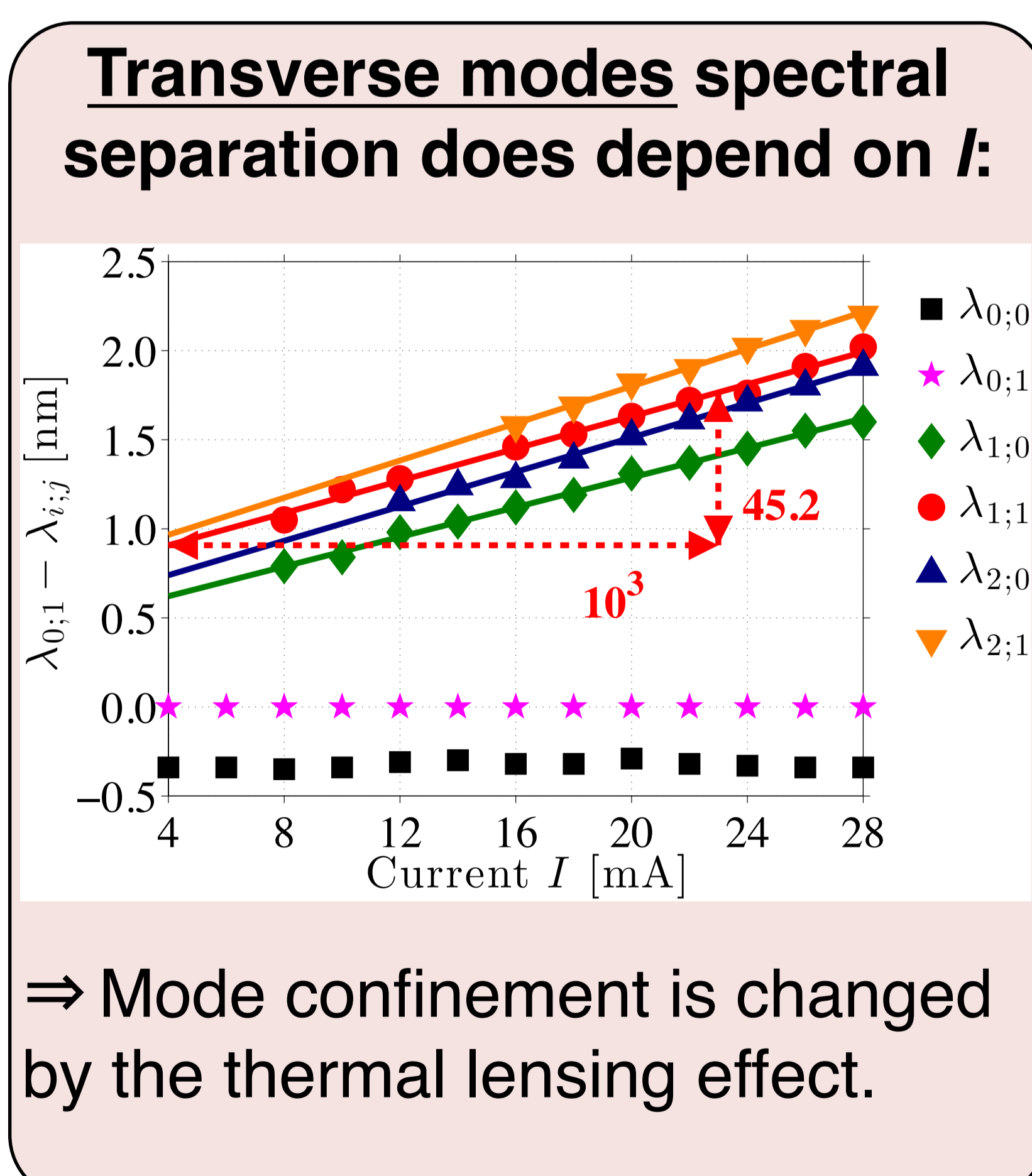
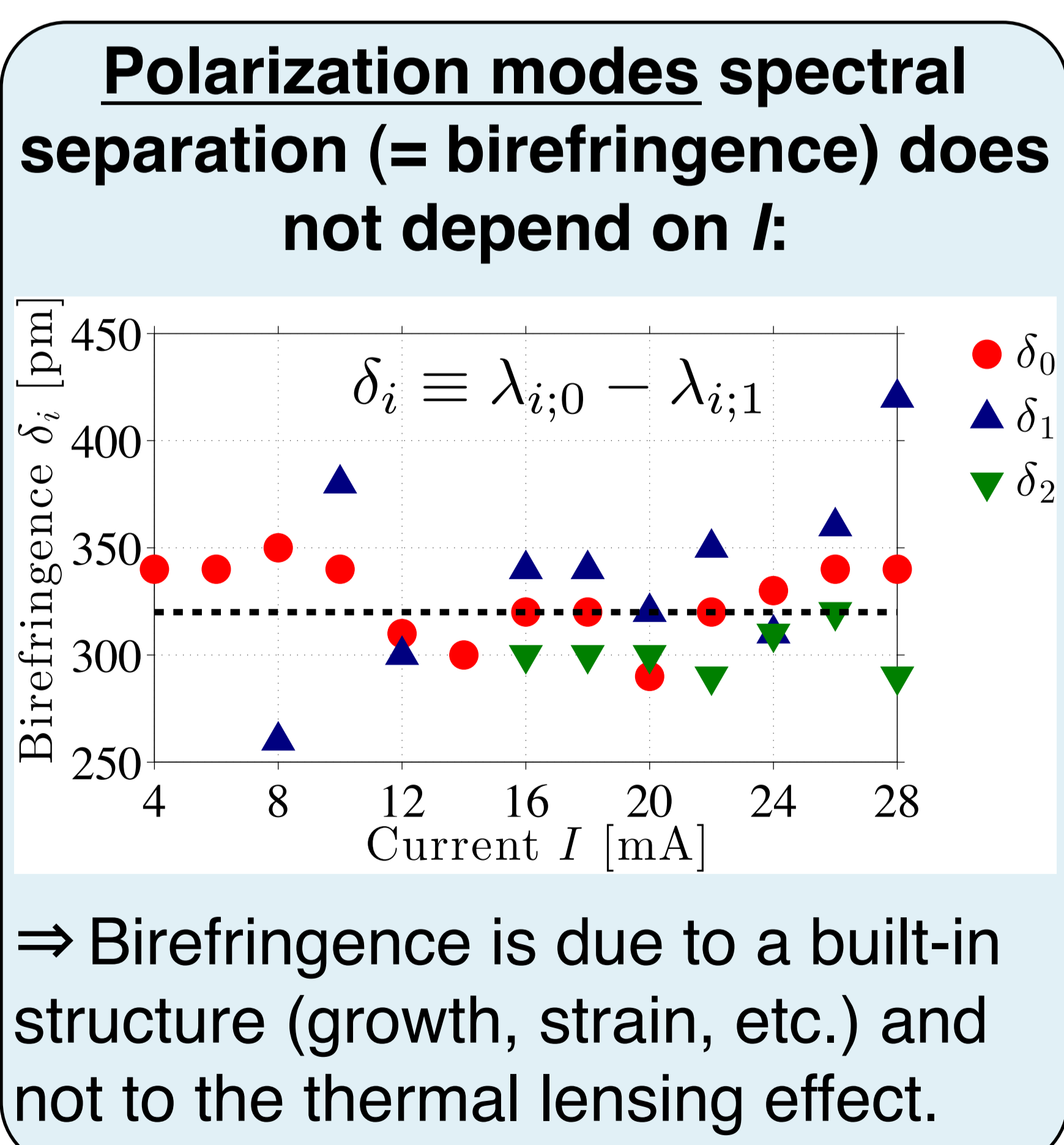
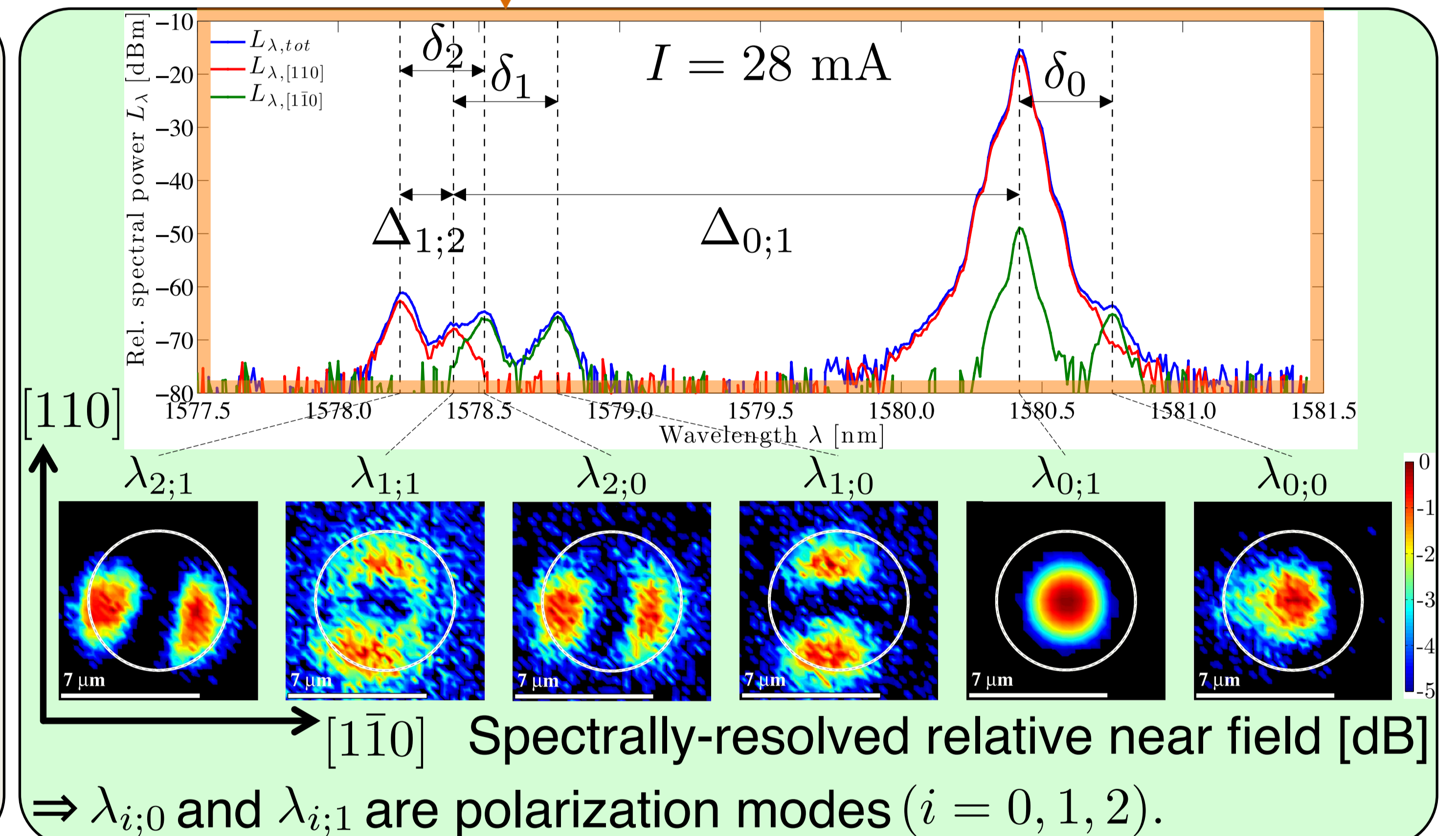
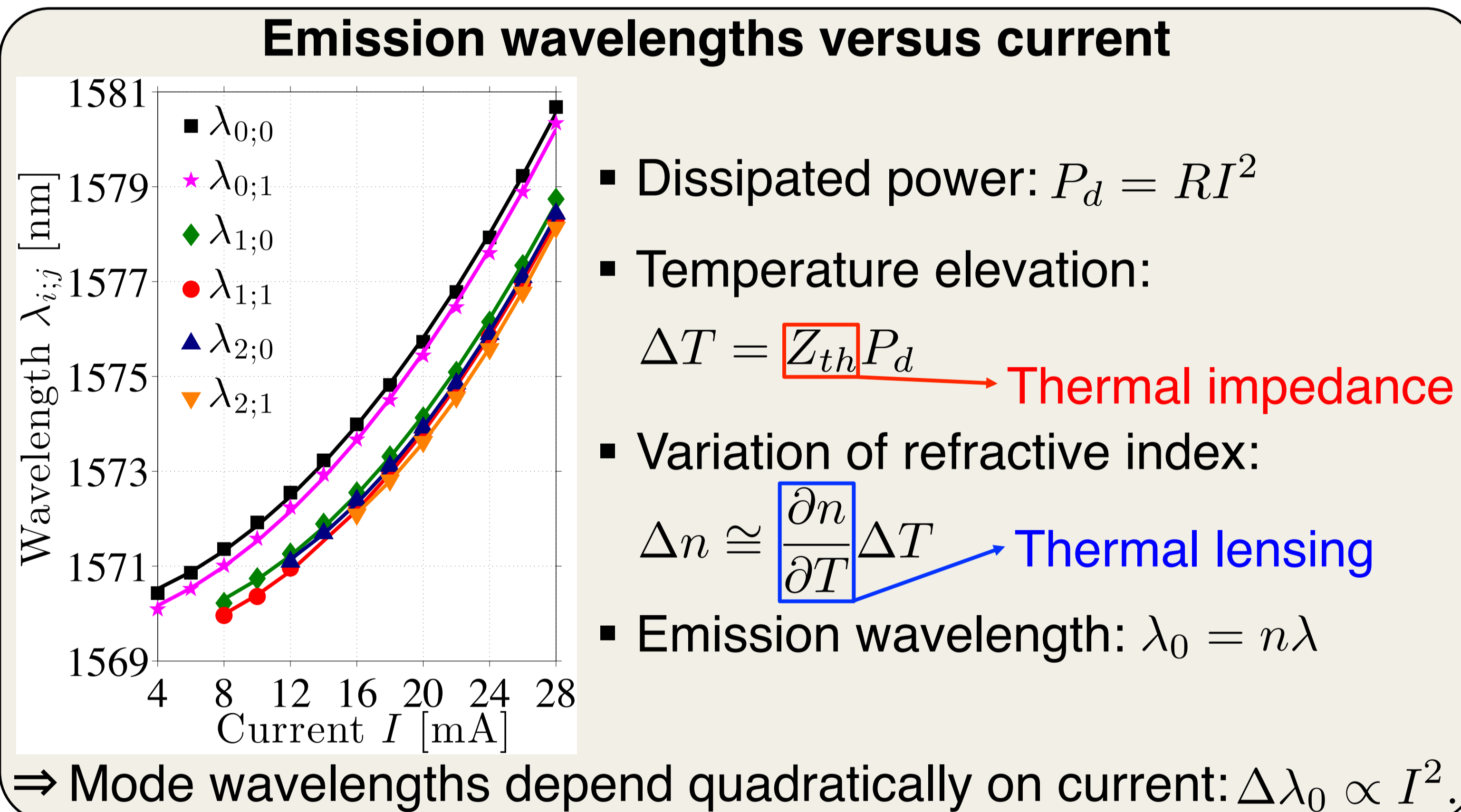
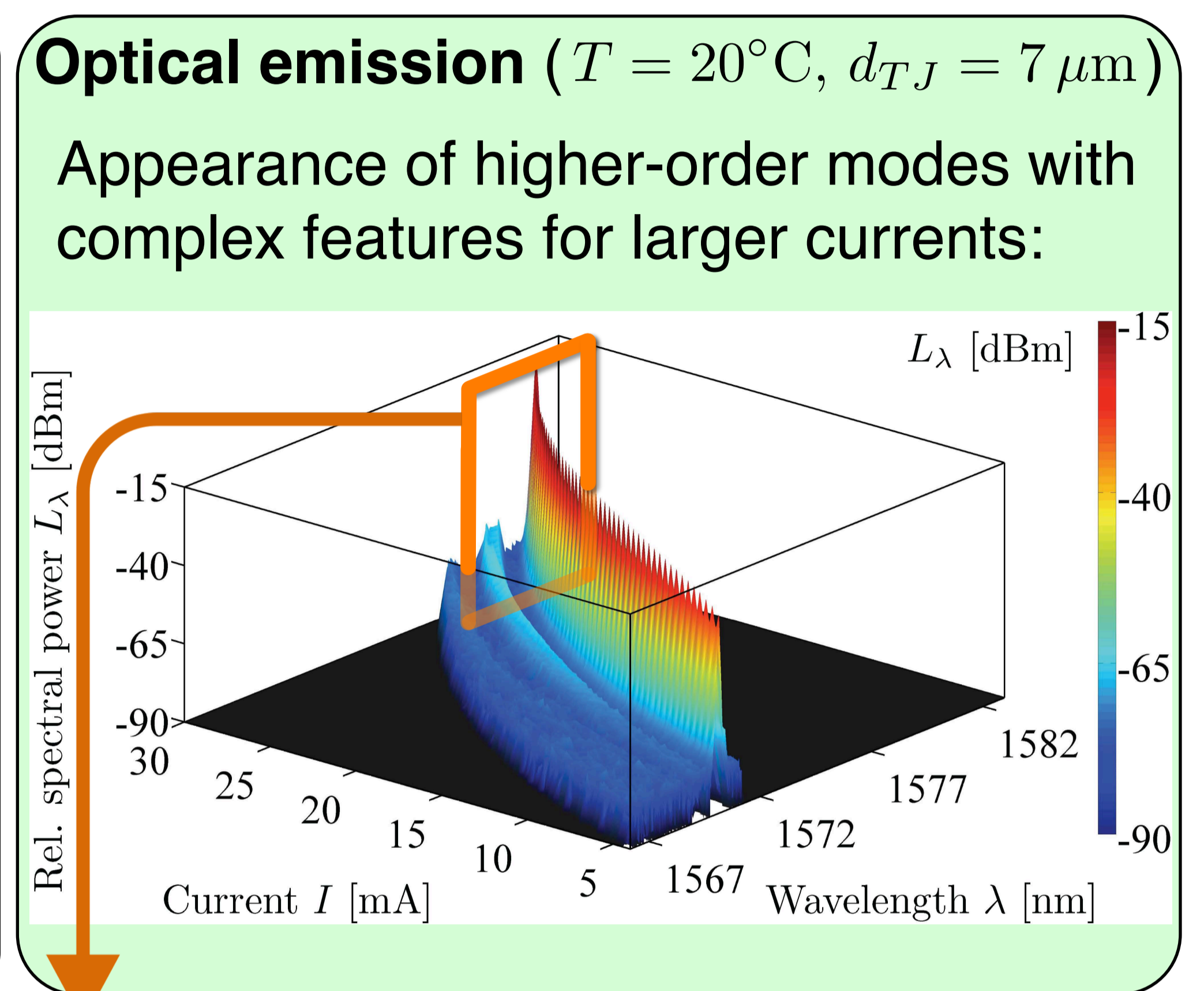
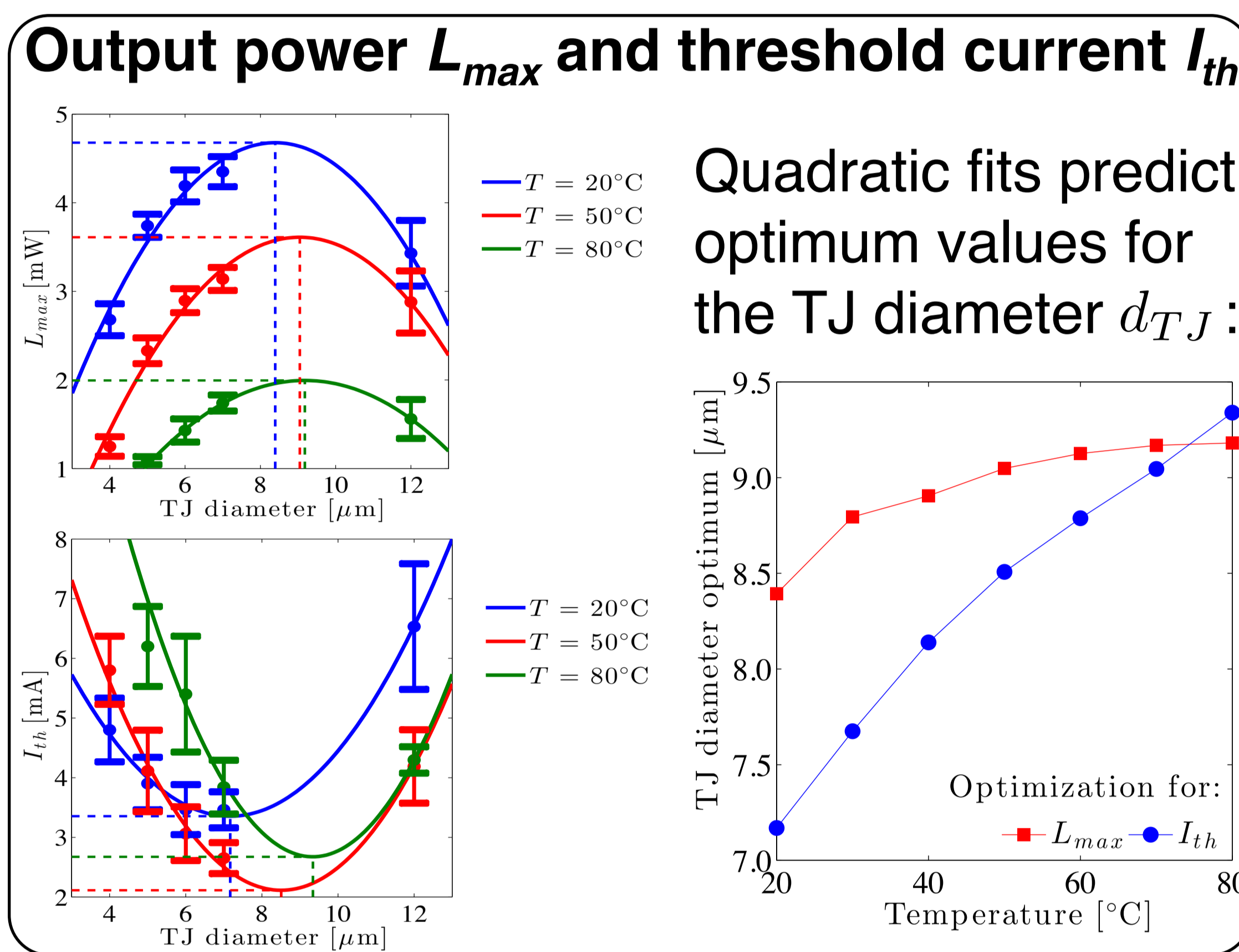
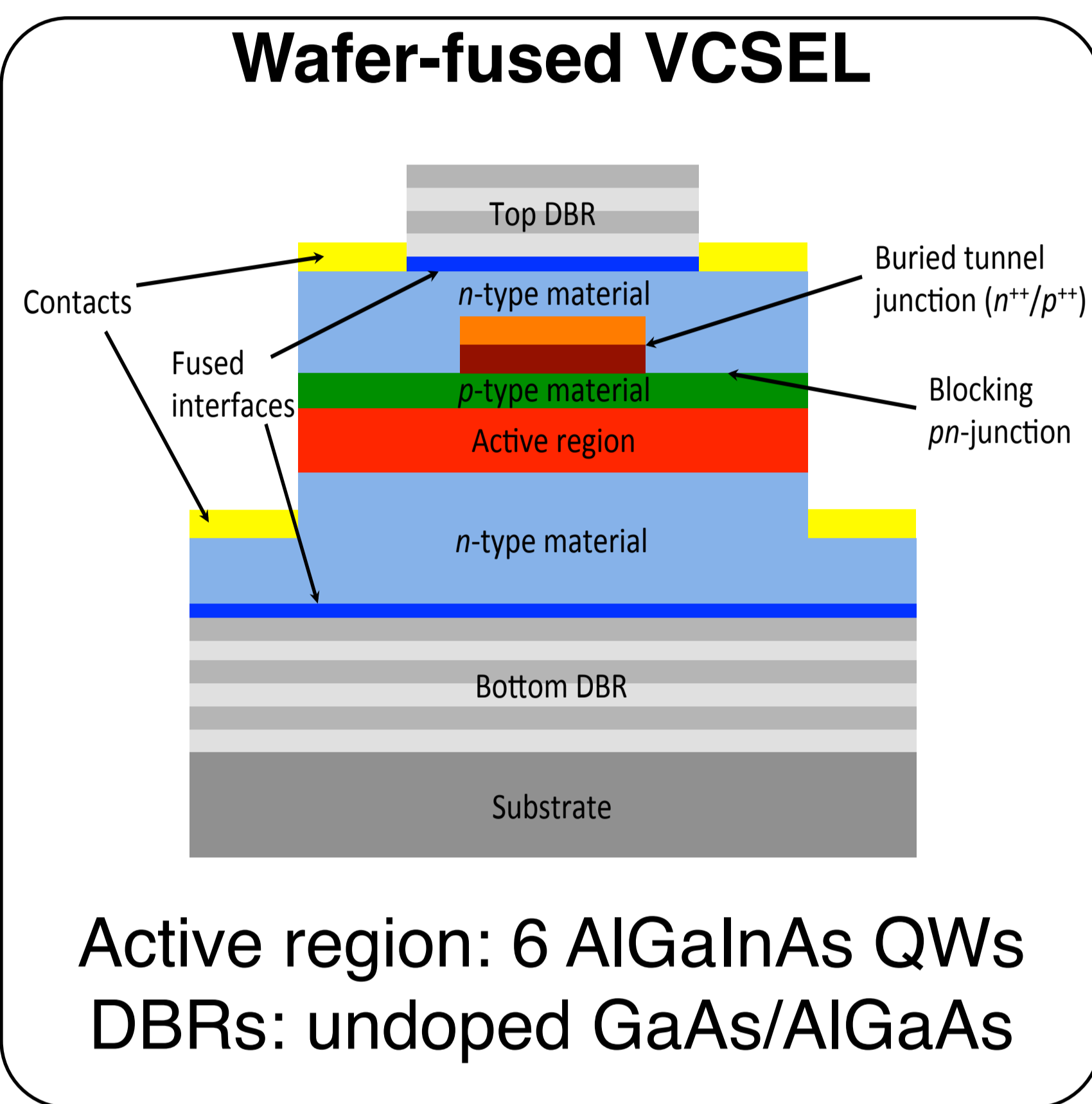


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- Statistical study of the influence of the tunnel junction (TJ) diameter on the performance of long-wavelength VCSELs.
- Study of the higher-order transverse modes and of the polarization modes: spectral analysis, near field mapping and control.



- ✓ Establishment of clear relationships of threshold current and maximal output power of the VCSELs as functions of the temperature and tunnel junction diameter.
- ✓ Identification of two empirical parameters describing the mode structure:  $\delta$  and  $s$ .
- ✓ Further calibration of VCSEL numerical models.
- ✓ Present results are the basis for the study of the influence of intra-cavity patterns to stabilize the polarization and to discriminate the high-order transverse modes.